

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Keizo Yamada

Serial No.: 09/865,528

Group Art Unit: 2829

Filed: May 29, 2001

Examiner: Nguyen, Vinh P.

For: SEMICONDUCTOR DEVICE TEST METHOD AND SEMICONDUCTOR DEVICE  
TESTER

Commissioner of Patents  
Washington, D.C. 20231

**EXCESS CLAIM FEE PAYMENT LETTER**

Sir:

Transmitted herewith is an amendment in the above-identified application. The fee has been calculated and is transmitted as shown below.

	<u>AFTER AMENDMENT</u>	<u>PREV. PAID FOR</u>	<u>EXTRA CLAIMS PRESENT</u>	<u>RATE</u>	<u>FEE DUE</u>
Total Claims	26 -	25	= 1	x \$18.00	\$ 18.00
Indep. Claims	9 -	8	= 1	x \$84.00	\$ 84.00

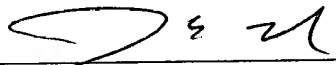
**TOTAL ADDITIONAL FEE FOR THIS AMENDMENT**

**\$ 102.00**

A check in the amount of \$102.00 to cover the excess claim fees. A duplicate copy of this sheet is enclosed. The Commissioner is authorized charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully Submitted,

Date: 3/12/03

  
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